

Search Notes

Application/Control No.

10/780,932

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

CHEN, KUN-HONG

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E51.005, E33.064, E31.126 & 79	4/1/2005	C.C.
257	E29.151	4/1/2005	C.C.
257	E23.157	4/1/2005	C.C.
257	758 & 449	4/1/2005	C.C.
257	749 & 347	4/1/2005	C.C.
257	350 & 43	4/1/2005	C.C.
438	609	4/1/2005	C.C.
174	255-258	4/1/2005	C.C.
349	139 & 149	4/1/2005	C.C.
349	152	4/1/2005	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	4/1/2005	C.C.
Consulted with Sheila Clark 257/43, 449, 758 TFT array and ITO	4/1/2005	C.C.
Consulted with John Vigushin 174/255 - 258	4/1/2005	C.C.
Consulted with George Fourson 257/79, 347, 350 749, E33.064 and E23.157 438/609	4/1/2005	C.C.
Consulted with David Graybill 257/449, 749, 758, E51.005, E33.064, E31.126 and E29.151	4/1/2005	C.C.
Consulted with George Eckert 349/139,149 and 152	4/1/2005	C.C.